



## CAS300M12BM2

### 1.2kV, 5.0 mΩ All-Silicon Carbide Half-Bridge Module

Z-FET™ MOSFET and Z-Rec™ Diode

$V_{DS}$	= 1.2 kV
$E_{sw,Total@300A}$	= 12.0 mJ
$R_{DS(on)}$	= 5.0 mΩ

#### Module Features

- Ultra Low Loss
- High-Frequency Operation
- Zero Reverse Recovery Current from Diode
- Zero Turn-off Tail Current from MOSFET
- Normally-off, fail-safe device operation
- Ease of paralleling
- Copper baseplate and aluminum nitride insulator

Package 62 mm x 106 mm x 30 mm



#### System Benefits

- Enables compact and lightweight systems
- High efficiency operation
- Mitigates over-voltage protection
- Reduces thermal requirements
- Enables simplified topologies

#### Applications

- Induction Heating
- Motor Drives
- Solar and Wind Inverters
- UPS and SMPS
- Traction

Part Number	Package	Marking
CAS300M12BM2	Half Bridge Module	CAS300M12BM2

#### Maximum Ratings ( $T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
$V_{DSmax}$	Drain – Source Voltage	1.2	kV		
$V_{GSmax}$	Gate – Source Voltage	-10/+25	V	Absolute maximum values	
$V_{GSop}$	Gate – Source Voltage	-5/+20	V	Recommended operational values	
$I_D$	Continuous Drain Current	404	A	$V_{GS} = 20 \text{ V}, T_C = 25^\circ\text{C}$	Fig 20
		285	A	$V_{GS} = 20 \text{ V}, T_C = 90^\circ\text{C}$	
$I_{Dpulse}$	Pulsed Drain Current	1500	A	Pulse width $t_P = 200 \mu\text{s}$ repetition rate limited by $T_{J(max)}$ , $T_C = 25^\circ\text{C}$	
$T_{Jmax}$	Junction Temperature	150	°C		
$T_C$	Case and Storage Temperature Range	-40 to +125	°C		
$P_{tot}$	Maximum Power Dissipation	1660	W	$T_C = 25^\circ\text{C}, T_J = 150^\circ\text{C}$	
$V_{isol}$	Case Isolation Voltage	4.0	kV	AC, 50 Hz, 1 min	
$L_{stray}$	Stray Inductance	14	nH	Measured between terminals 2 and 3	
M	Mounting Torque	5	Nm	To heatsink and terminals	
G	Weight	300	g		
	Clearance Distance	12	mm	Terminal to terminal	
	Creepage Distance	30	mm	Terminal to terminal	
		40	mm	Terminal to baseplate	



### Electrical Characteristics ( $T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value			Unit	Test Conditions	Notes
		Min	Typ	Max			
$V_{(\text{BR})\text{DSS}}$	Drain – Source Breakdown Voltage	1.2			kV	$V_{GS} = 0 \text{ V}, I_{DS} = 1 \text{ mA}$	
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	2.3		V	$V_{DS} = 10 \text{ V}, I_{DS} = 15 \text{ mA}$	Fig 11
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current		500	2000	$\mu\text{A}$	$V_{DS} = 1.2 \text{ kV}, V_{GS} = 0 \text{ V}$	
			1000			$V_{DS} = 1.2 \text{ kV}, V_{GS} = 0 \text{ V}$ $T_J = 150^\circ\text{C}$	
$I_{\text{GSS}}$	Gate-Source Leakage Current		1	100	nA	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	
$R_{DS(\text{on})}$	Drain-Source On-State Resistance		5.0	5.7	$\text{m}\Omega$	$V_{GS} = 20 \text{ V}, I_{DS} = 300 \text{ A}$	Fig 4, 5 and 6
			8.6	9.8		$V_{GS} = 20 \text{ V}, I_{DS} = 300 \text{ A}, T_J = 150^\circ\text{C}$	
			94.8			$V_{DS} = 20 \text{ V}, I_{DS} = 300 \text{ A}$	
$g_{fs}$	Transconductance		93.3		S	$V_{DS} = 20 \text{ V}, I_{DS} = 300 \text{ A}, T_J = 150^\circ\text{C}$	Fig 7
$C_{\text{ISS}}$	Input Capacitance		11.7		nF	$V_{DS} = 600 \text{ V} f = 200 \text{ kHz}, V_{AC} = 25 \text{ mV}$	Fig 17, 18
$C_{\text{OSS}}$	Output Capacitance		2.55				
$C_{\text{RSS}}$	Reverse Transfer Capacitance		0.07				
$t_{d(\text{on})}$	Turn-On Delay Time		76			$V_{DD} = 600 \text{ V}, V_{GS} = -5/20 \text{ V}$ $I_D = 300 \text{ A}, R_G(\text{ext}) = 2.5 \Omega$ , Timing relative to $V_{DS}$ Per IEC60747-8-4 pg 83	Fig 24
$t_r$	Rise Time		68			Inductive Load	
$t_{d(\text{off})}$	Turn-Off Delay Time		168				
$t_f$	Fall Time		43				
$E_{\text{ON}}$	Turn-On Switching Energy		6.05			$V_{DS} = 600 \text{ V}, V_{GS} = -5 / 20 \text{ V}$ $I_{DS} = 300 \text{ A}, R_G = 2.5 \Omega$ , Inductive Load	Fig 25
$E_{\text{OFF}}$	Turn-Off Switching Energy		5.95				

### Free-Wheeling Diode Characteristics

Symbol	Parameter	Value			Unit	Test Conditions	Notes
		Min	Typ	Max			
$V_{SD}$	Diode Forward Voltage		1.7	2.0	V	$I_{SD} = 300 \text{ A}, T_J = 25^\circ\text{C}, V_{GS} = 0 \text{ V}$	Fig 8, 9 and 10
			2.2	2.5	V	$I_{SD} = 300 \text{ A}, T_J = 150^\circ\text{C}, V_{GS} = 0 \text{ V}$	
$Q_c$	Total Capacitive Charge		3.2		$\mu\text{C}$		

Note: The reverse recovery is purely capacitive.

### Gate Charge Characteristics

Symbol	Parameter	Value			Unit	Test Conditions	Notes
		Min	Typ	Max			
$Q_{GS}$	Gate to Source Charge		166		nC	$V_{DS} = 800 \text{ V}, V_{GS} = -5 /+ 20 \text{ V}$ $I_{DS} = 300 \text{ Amps}$ Per JEDEC24 pg 27	Fig 12
$Q_{GD}$	Gate to Drain Charge		475				
$Q_g$	Total Gate Charge		1025				
$R_g$	Internal Gate Resistance		3.0			$f = 200 \text{ kHz}, V_{AC} = 25 \text{ mV}$	

### Thermal Characteristics

Symbol	Parameter	Value			Unit	Test Conditions	Notes
		Min	Typ	Max			
$R_{\theta\text{JCM}}$	Thermal Resistance Junction to Case for MOSFET		0.070	0.075	$^\circ\text{C}/\text{W}$	$T_C = 90^\circ\text{C}, T_J = 150^\circ\text{C}$ $P_{\text{dis}} = P_{\text{max}}$	Fig 17
$R_{\theta\text{JCD}}$	Thermal Resistance Junction to Case for Diode		0.073	0.076			

## Typical Performance

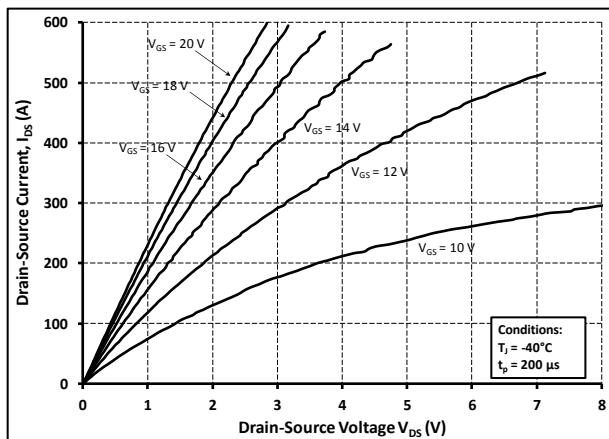


Fig 1. Typical Output Characteristics  $T_J = -40^\circ\text{C}$

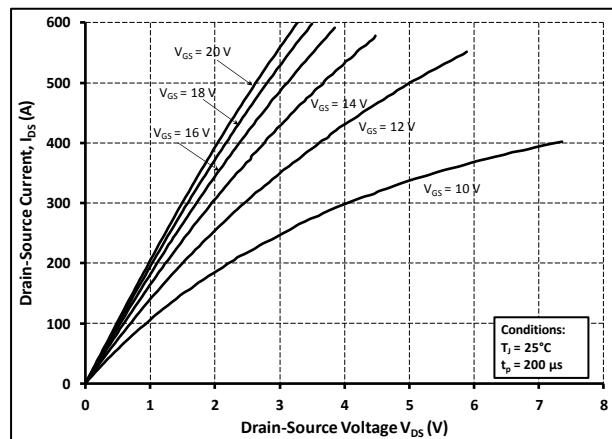


Fig 2. Typical Output Characteristics  $T_J = 25^\circ\text{C}$

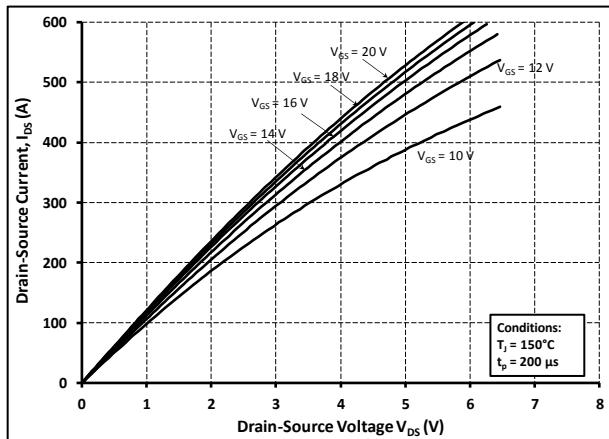


Fig 3. Typical Output Characteristics  $T_J = 150^\circ\text{C}$

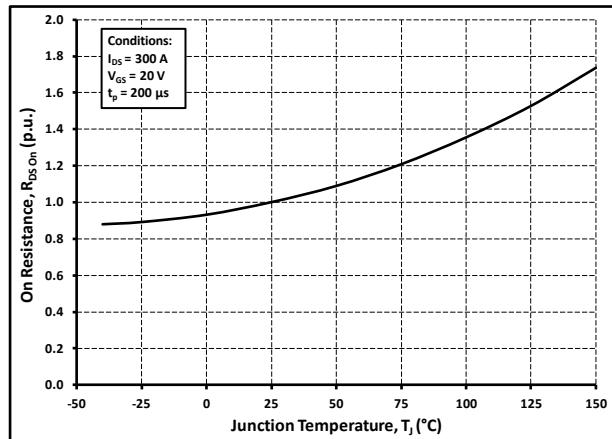


Fig 4. Normalized On-Resistance vs. Temperature

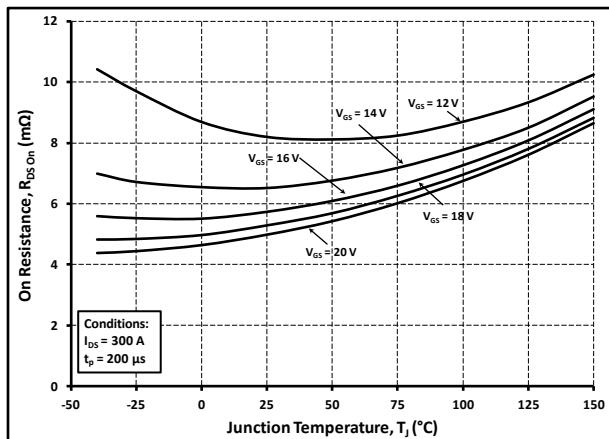


Fig 5. Typical On-Resistance vs. Temperature and Gate Voltage

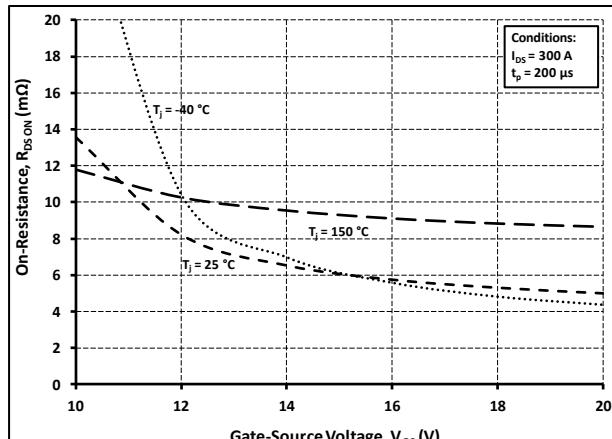


Fig 6. Typical On-Resistance vs. Gate Voltage

## Typical Performance

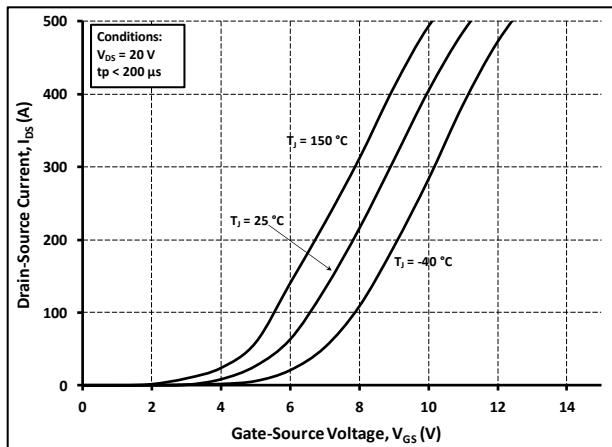


Fig 7. Typical Transfer Characteristic For Various Temperatures

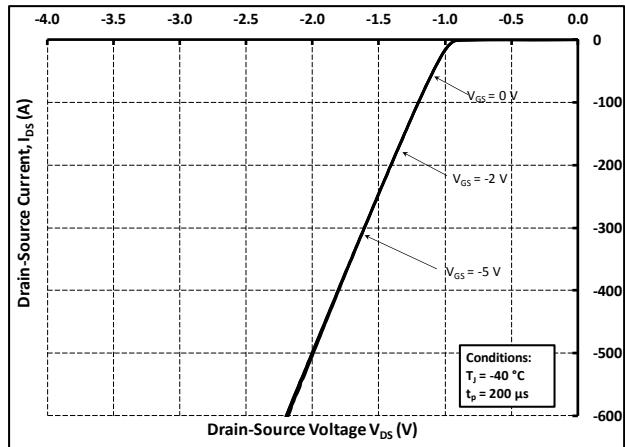


Fig 8. Typical Diode Behavior  $T_J = -40^\circ\text{C}$

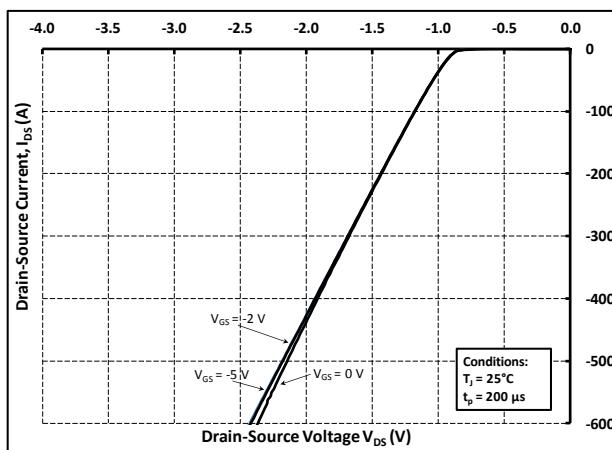


Fig 9. Typical Diode Behavior  $T_J = 25^\circ\text{C}$

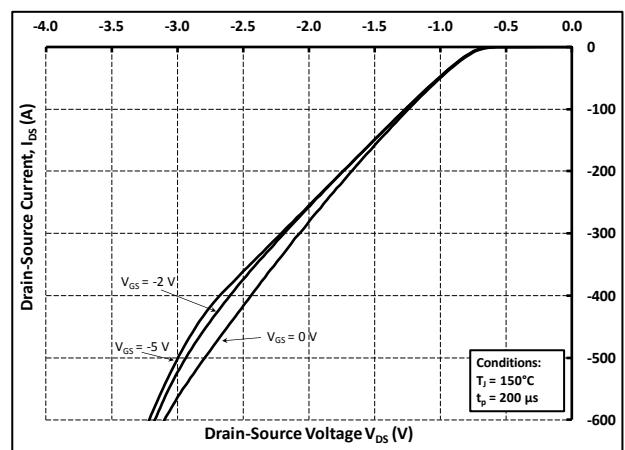


Fig 10. Typical Diode Behavior  $T_J = 150^\circ\text{C}$

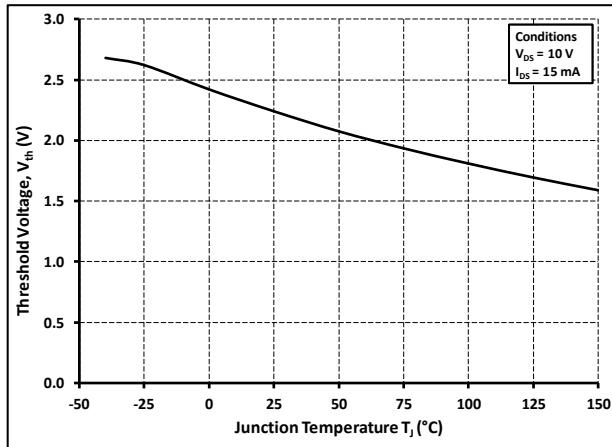


Fig 11. Typical Threshold Voltage vs. Temperature

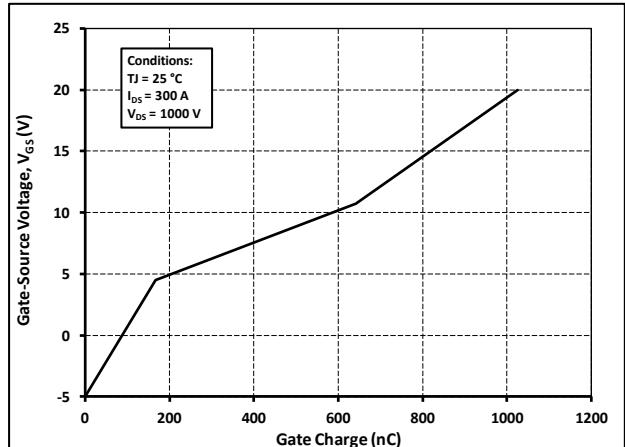


Fig 12. Typical Gate Charge

## Typical Performance

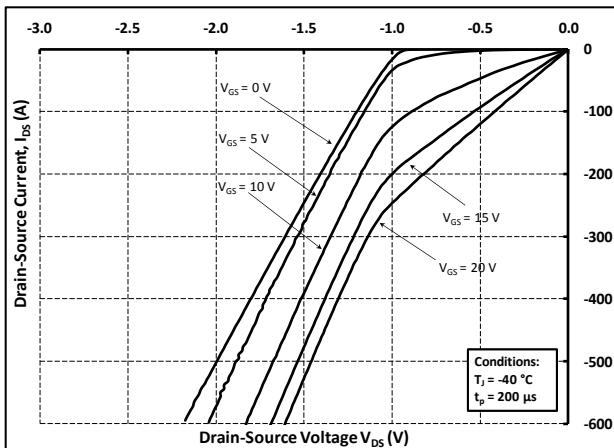


Fig 13. Typical 3<sup>rd</sup> Quadrant Behavior  $T_J = -40^\circ\text{C}$

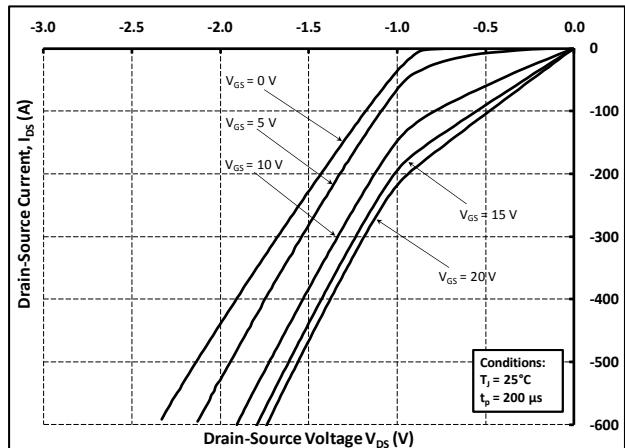


Fig 14. Typical 3<sup>rd</sup> Quadrant Behavior  $T_J = 25^\circ\text{C}$

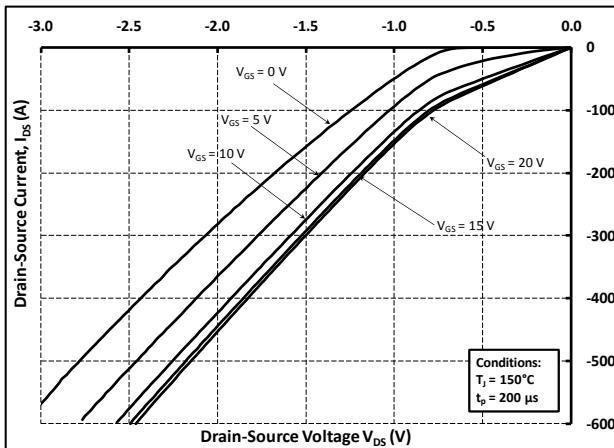


Fig 15. Typical 3<sup>rd</sup> Quadrant Behavior  $T_J = 150^\circ\text{C}$

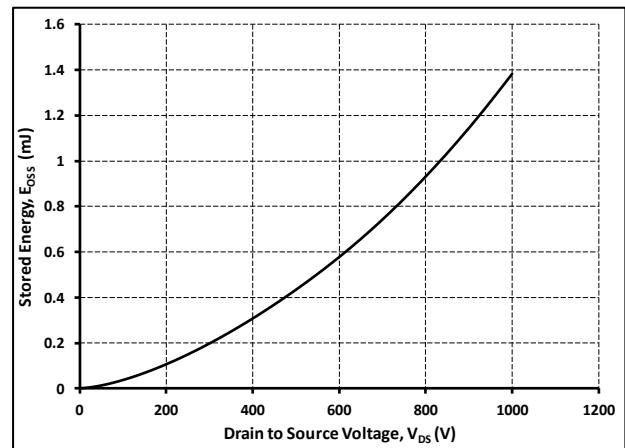


Fig 16. Typical Output Capacitor Stored Energy

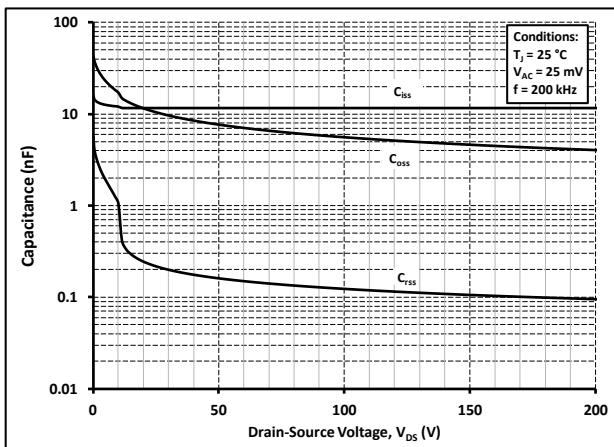


Fig 17. Typical Capacitances vs. Drain-Source Voltage. (0-200V)

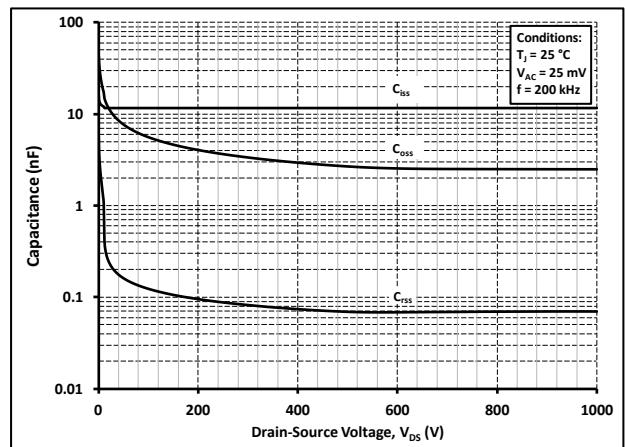


Fig 18. Typical Capacitances vs. Drain-Source Voltage. (0-1000V)

## Typical Performance

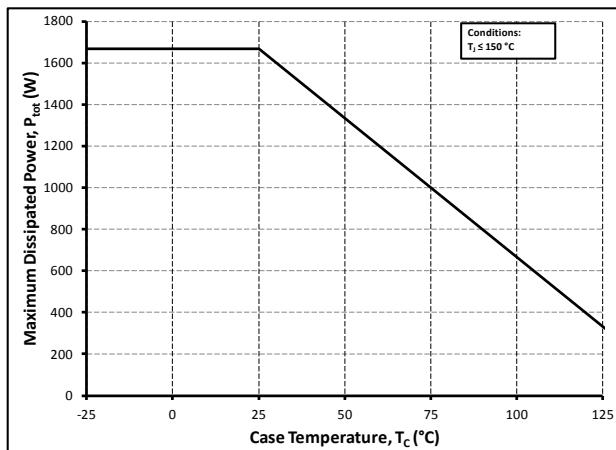


Fig 19. Max. Continuous Power Derating Curve vs. Case Temperature.

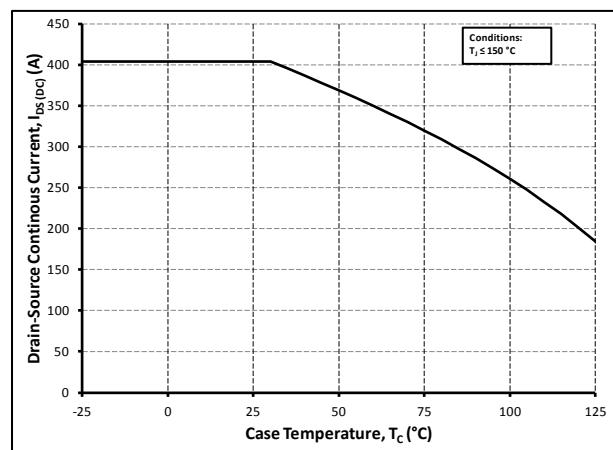


Fig 20. Max. Continuous Current Derating Curve vs. Case Temperature

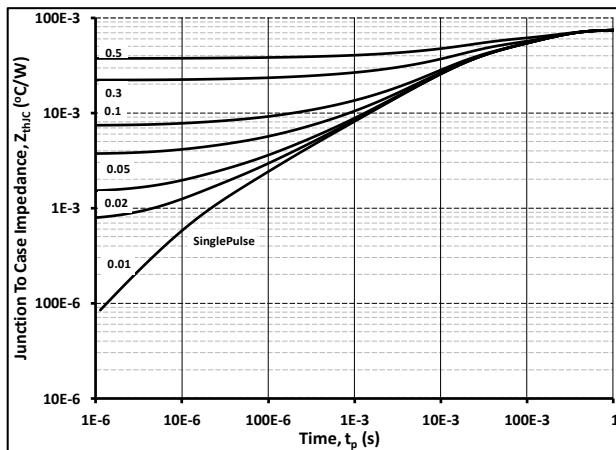


Fig 21. Typical Transient Thermal Impedance - MOSFET

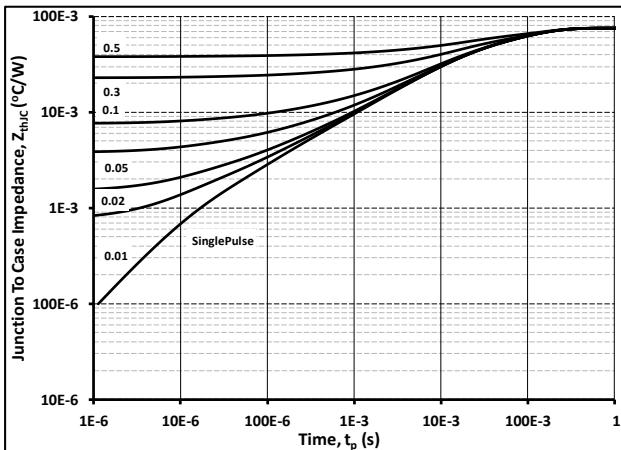


Fig 22. Typical Transient Thermal Impedance - DIODE

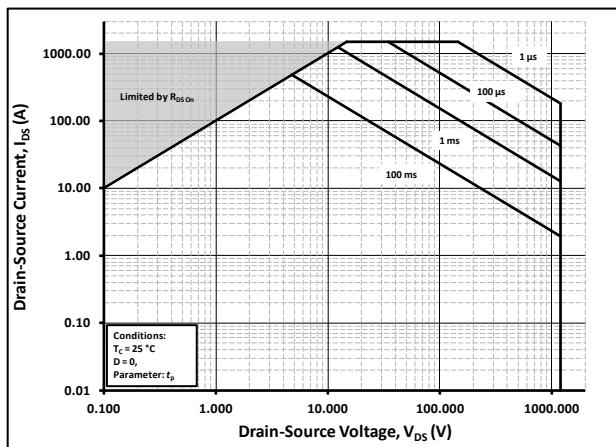


Fig 23. MOSFET Safe Operating Area

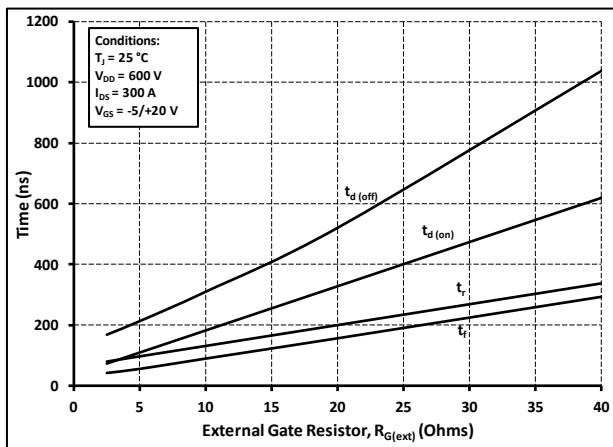


Fig 24. Typical Inductive Switching Time vs Gate Resistance ( $V_{DD} = 600V$ ,  $I_D = 300A$ )

## Typical Performance

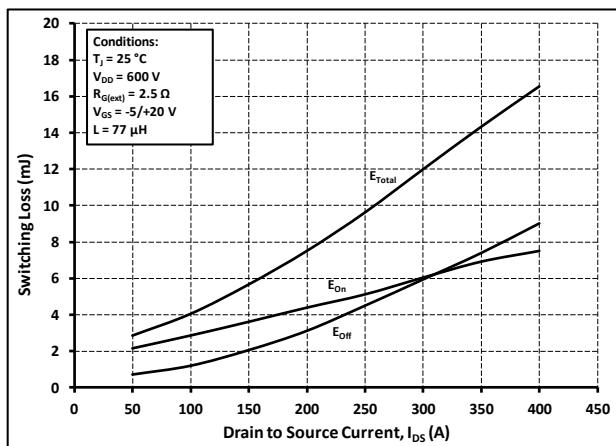


Fig 25. Typical Clamped Inductive Switching Energy vs Drain Current ( $V_{DD} = 600\text{V}$ )

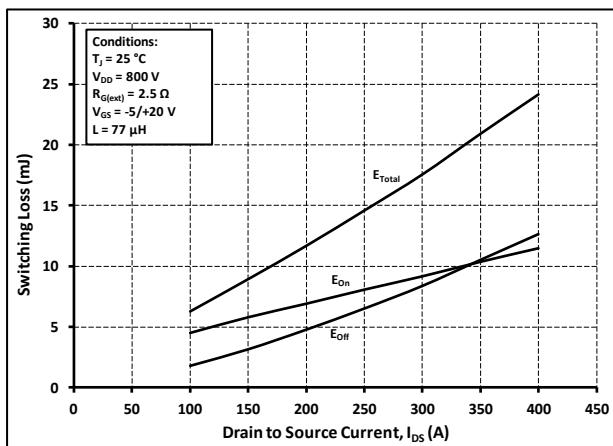


Fig 26. Typical Clamped Inductive Switching Energy vs Drain Current ( $V_{DD} = 800\text{V}$ )

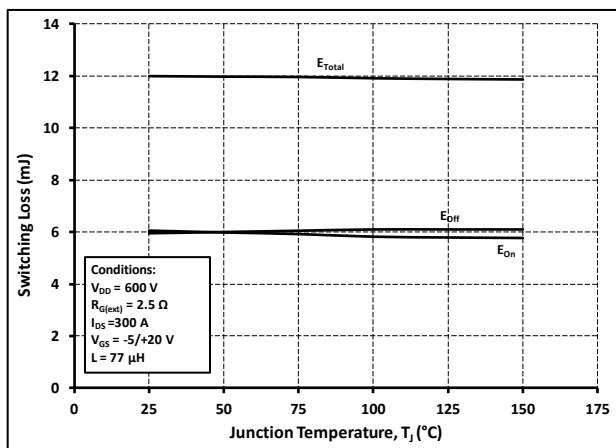


Fig 27. Typical Switching Loss vs. Temperature

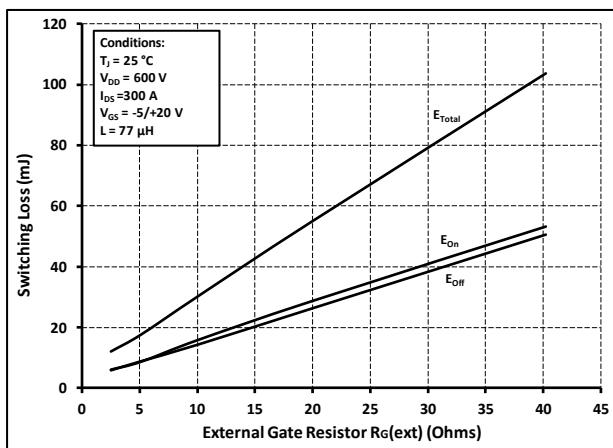
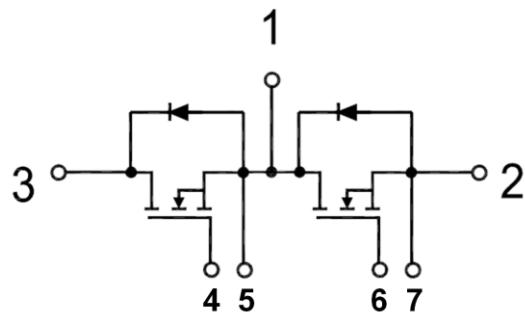


Fig 28. Typical Switching Loss vs. Gate Resistance



## Schematic



## Mechanical Characteristics (in mm)

